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ELECTRON DIFFRACTION CONTRAST OF SLIP TRACES AND SLIP BANDS K. Scheerschmidt and U. Richter

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When dislocations are moved in thin foils by stresses due to the electron beam or during deformation experiments the remaining electron diffraction contrast consists of pairs of black-white lines (slip traces) or bright and dark bands (slip bands). The slip traces which can mostly be seen for a short time only are the places where the slip plane cuts the surfaces.

The contrast of slip traces can be well explained on the assumption that a surface layer of oxide, carbon or chemical deposit exists which fixes the slip step caused by the moving dislocation /A. Howie, M.J. Whelan, Proc. Roy. Soc. A267, 206 (1962)/. This slip step can be represented by a long dislocation left in or just below the surface layer plus an image dislocation (Fig. 1a), where the separation of the dislocations in each dipole is about $0.1 \, \xi_3$ (bright-field curves 1 and 2).

Fig. 2 shows an example of slip band contrast in aluminium /F.Appel, U.Messerschmidt, phys.stat.sol.(a)34,175(1976)/. It can be assumed that the surface layer consists of Al₂O₃

which is the cause of the strong slip band contrast.

For the explanation of the slip band contrast the model using two dislocation dipoles must be extended to an infinite series of image dislocations for a correct consideration of the surface layer /A.K.Head, Phil.Mag. 44, 92(1953)/. Already two image dislocations (Fig. 1b, bright-field curves 3 and 4) give a sufficient interpretation of the contrast of the whole slip band /K. Scheerschmidt, Proc. 15. Czech. Conf. Electron Micr., Prag 1977, p. 619 and Proc. 9. Conf. Electron

Micr., Dresden, 1978, p. 43/.
For each slip system the analysis of the imaging conditions of Fig. 2 gives six different possibilities to characterize the slip trace model with two image dislocations. If only reflexes of (200) and (220) type are considered, then 15 different diffraction conditions exist for which in Fig. 3 the bright-field contrast profiles are calculated. Hence it follows that the slip bands are dark if n>0, bright if n<0 and in the case n=0 they are determined from the parameter m. Using this result it should be possible to determine the slip system and the slipped dislocation by taking two experimental

pictures with orthogonal reflexes.

Fig. 4 shows the dependence of the calculated slip band contrast on the diffraction parameters and on the parameters describing the surface layer. The dotted curve is equivalent to the curve n=1 (iii) of Fig. 3. The parameters d and zoin-fluence the contrast of the slip traces and do not change the slip band brightness. The parameters w and & determine the visibility of the slip bands, good contrast of the slip bands should be expected near the Bragg-orientation (w €0) and if a great difference of shear modulus of substrate and surface layer is obtained $(|\infty| \gg 0)$.

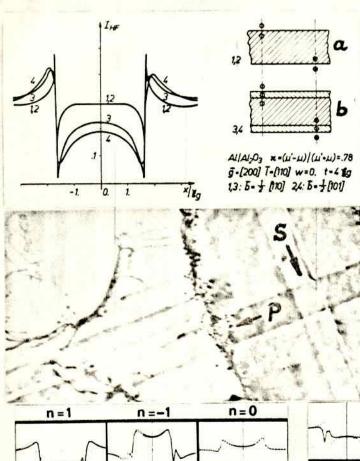
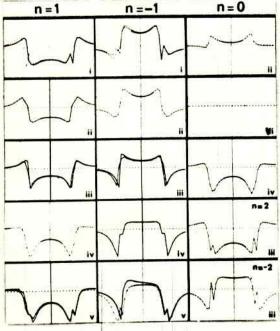
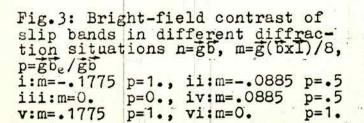


Fig.1: Computed brightfield slip trace contrast
assuming the model of a
dislocation at either
surface of the foil just
below the surface layer:
a) one image dislocation
b) two image dislocations

shear moduli
diffraction vector
dislocation direction
w deviation parameter
foil thickness
Burgers-vector
extinction distance

Fig.2: Slip bands in aluminium: primary slip system P, secondary slip system S, slip trace orientation <110>, tensile axis <15 4 0>, foil plane \$00\$, slip system \$111\$<110>





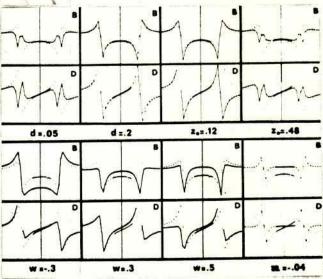


Fig.4: Bright- and darkfield contrast, B and D resp., of slip bands under different calculation conditions:

- d thickness of the surface layer assumed
- zo depth of the dislocation representing the slip trace below surface layer (the equilibrium value is determined by d and &)